



US00D769752S

(12) **United States Design Patent** (10) **Patent No.:** **US D769,752 S**
Teranishi et al. (45) **Date of Patent:** **** Oct. 25, 2016**

(54) **PROBE PIN** 8,669,774 B2 * 3/2014 Kato G01R 1/06722
324/755.01
(71) Applicant: **OMRON Corporation**, Kyoto-shi, 8,808,038 B2 * 8/2014 Hwang G01R 1/06722
Kyoto (JP) 439/66
(72) Inventors: **Hirotsada Teranishi**, Osaka (JP); 9,130,290 B2 * 9/2015 Sakai H01R 13/2428
Takahiro Sakai, Moriyama (JP) D749,968 S * 2/2016 Huang D10/77
D750,987 S * 3/2016 Huang D10/80
9,322,846 B2 * 4/2016 Sakai G01R 1/06716

(73) Assignee: **OMRON CORPORATION**, Kyoto (JP)

(**) Term: **15 Years**

(21) Appl. No.: **29/530,266**

(22) Filed: **Jun. 15, 2015**

(30) **Foreign Application Priority Data**

Dec. 15, 2014 (JP) 2014-027895

(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/80**

(58) **Field of Classification Search**
USPC D10/78, 80; D13/133, 154
CPC G01R 1/067; G01R 1/06705; G01R
1/06711; G01R 1/06716; G01R 1/06722;
G01R 1/06727; G01R 1/06733; G01R
1/06738; G01R 1/06744; G01R 1/0675;
G01R 1/06766; G01R 1/06772; G01R
1/06777; G01R 1/06783; G01R 1/0678

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D229,184 S * 11/1973 Brown et al. D10/103
D507,197 S * 7/2005 Sun D10/72
D662,895 S * 7/2012 Kimura D13/154
D665,744 S * 8/2012 Yamauchi D13/133
D665,745 S * 8/2012 Yamauchi D13/133
8,366,496 B2 * 2/2013 Hsu G01R 1/0466
439/66
8,460,010 B2 * 6/2013 Kimura G01R 1/06722
439/66

FOREIGN PATENT DOCUMENTS

JP 2011-232181 A 11/2011
TW D157152 S 11/2013

OTHER PUBLICATIONS

Taiwanese Office Action issued in TW Appl. No. 104303166 on Oct. 27, 2015.
Taiwanese Office Action issued in TW Appl. No. 104303167 on Oct. 27, 2015.
Taiwanese Office Action issued in TW Appl. No. 104303168 on Oct. 27, 2015.

(Continued)

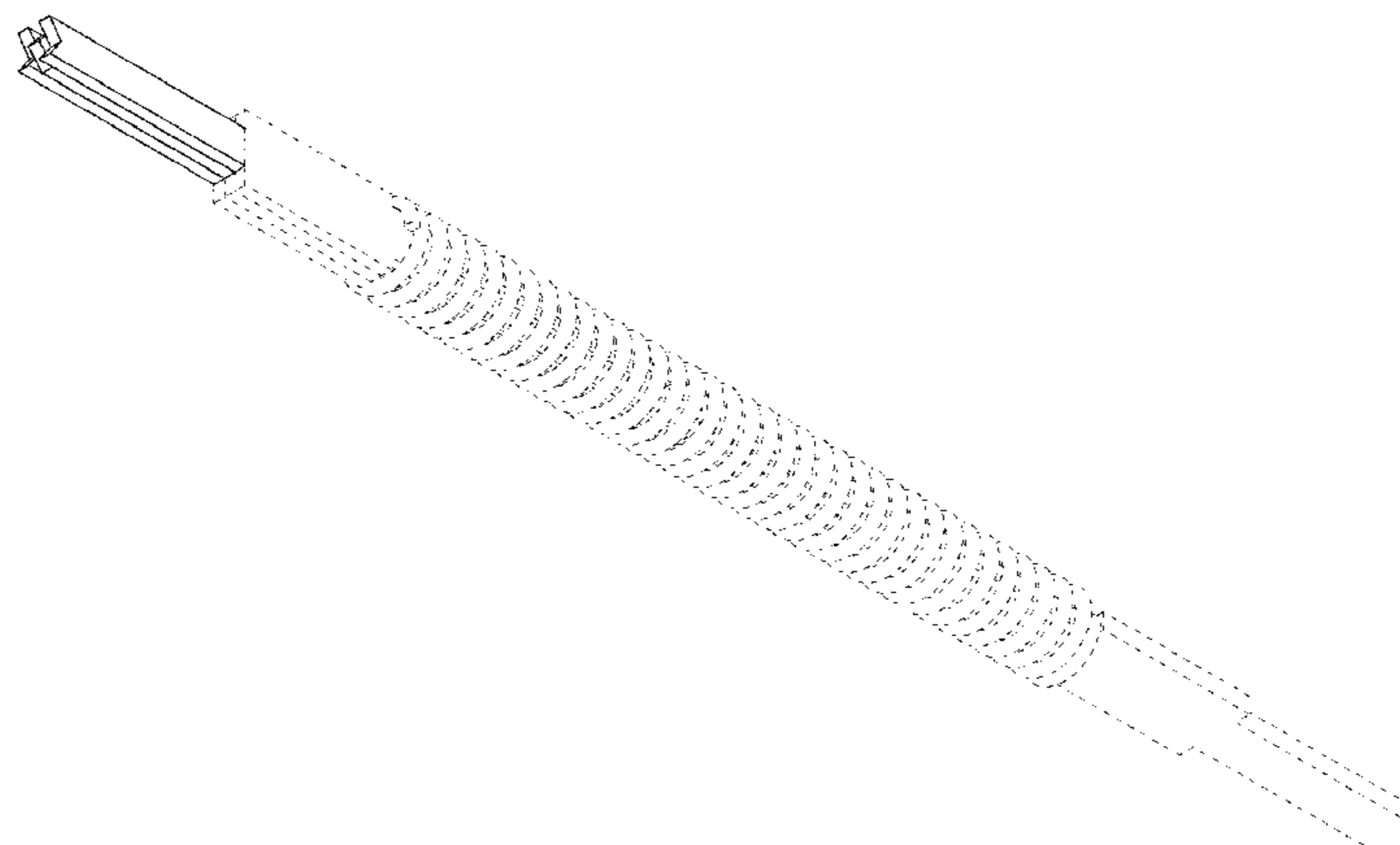
Primary Examiner — Antoine D Davis
(74) *Attorney, Agent, or Firm* — Sterne, Kessler, Goldstein & Fox P.L.L.C.

(57) **CLAIM**
The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a probe pin;
FIG. 2 is a front elevation view thereof;
FIG. 3 is a rear elevation view thereof;
FIG. 4 is a left side view thereof;
FIG. 5 is a right side view thereof;
FIG. 6 is a top plan view thereof; and,
FIG. 7 is a bottom plan view thereof.
The broken lines depict the environmental subject matter only and form no part of the claimed design. The dot-dash line represents the boundary of the claimed design.

1 Claim, 3 Drawing Sheets



(56)

References Cited

OTHER PUBLICATIONS

Taiwanese Office Action issued in TW Appl. No. 104303169 on Oct. 27, 2015.

U.S. Appl. No. 29/530,260, filed Jun. 15, 2015.

U.S. Appl. No. 29/530,261, filed Jun. 15, 2015.

U.S. Appl. No. 29/530,263, filed Jun. 15, 2015.

U.S. Appl. No. 29/530,264, filed Jun. 15, 2015.

U.S. Appl. No. 29/530,265, filed Jun. 15, 2015.

U.S. Appl. No. 29/530,394, filed Jun. 16, 2015.

U.S. Appl. No. 29/530,396, filed Jun. 16, 2015.

* cited by examiner

Fig. 1

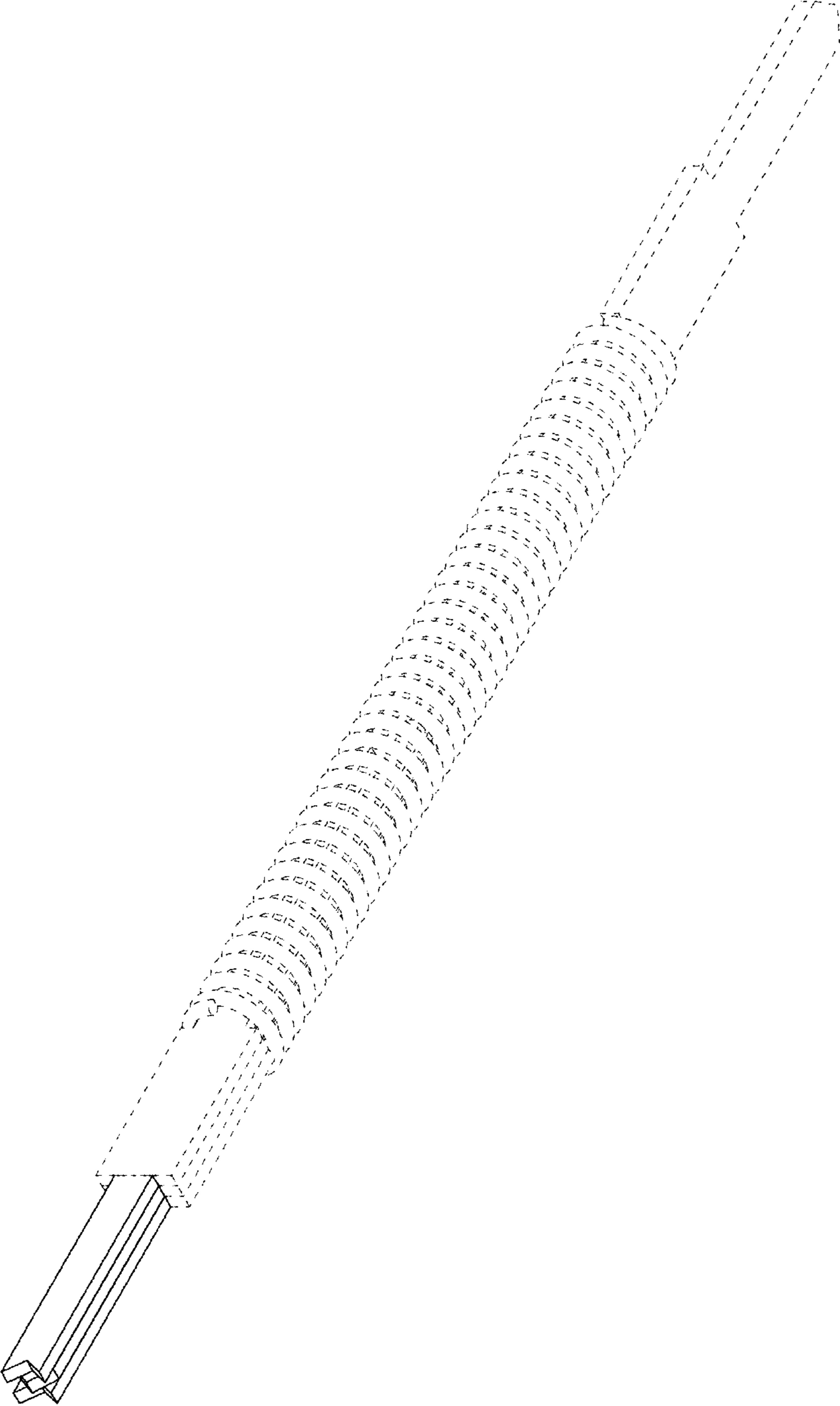


Fig. 2

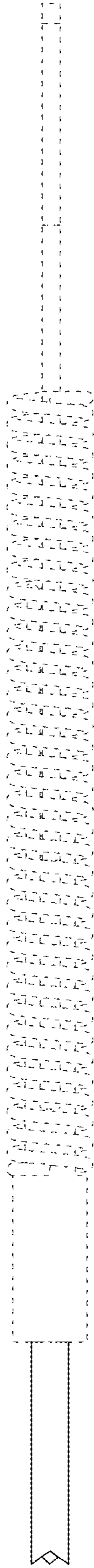


Fig. 3

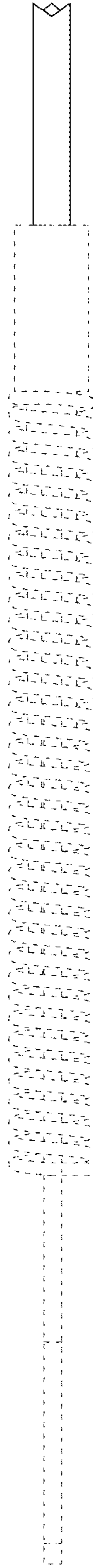


Fig. 4

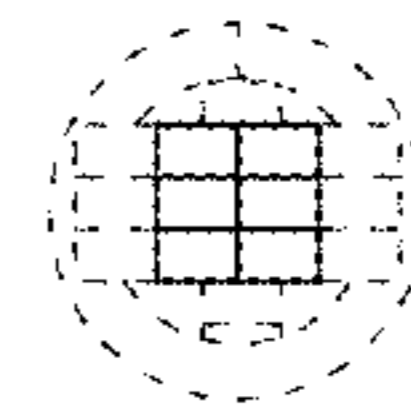


Fig. 5

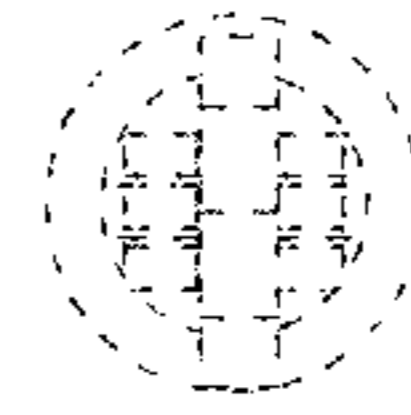


Fig. 6

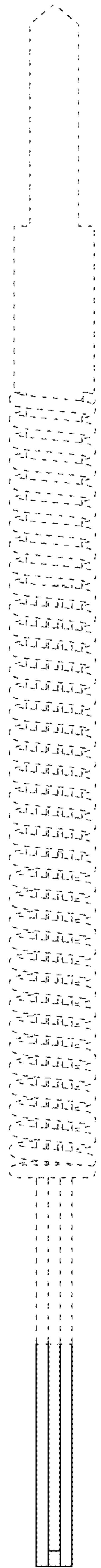


Fig. 7

